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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

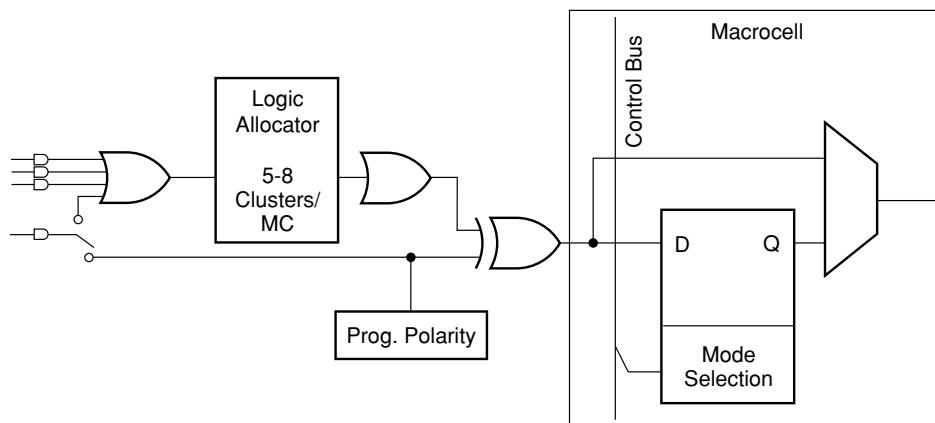
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	-
Number of Macrocells	512
Number of Gates	-
Number of I/O	256
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	352-LBGA
Supplier Device Package	352-SBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/m5lv-512-256-7sai

Macrocells

The macrocells for MACH 5 devices consist of a storage element which can be configured for combinatorial, registered or latched operation (Figure 3). The D-type flip-flops can be configured as T-type, J-K, or S-R operation through the use of the XOR gate associated with each macrocell.

Each PAL block has the capability to provide two input registers by using macrocells 0 and 15. In order to use this option, these macrocells must be accessed via the I/O pins associated with macrocells 3 and 12, respectively. Once the macrocell is used as an input register, it cannot be used for logic, so its clusters can be re-directed through the logic allocator to another macrocell. The

I/O pins associated with macrocells 0 and 15 can still be used as input pins. Although the I/O pins for macrocells 3 and 12 are used to connect to the input registers, these macrocells can still be used as “buried” macrocells to drive device logic via the matrix.



20446G-003

Figure 3. Macrocell Diagram

Control Generator

The control generator provides four configurable clock lines and three configurable set/reset lines to each macrocell in a PAL block. Any of the four clock lines and any of the three set/reset lines can be independently selected by any flip-flop within a block. The clock lines can be configured to provide synchronous global (pin) clocks and asynchronous product term clocks, sum term clocks, and latch enables (Figure 4). Three of the four global clocks, as well as two product-term clocks and one sum-term clock, are available per PAL block. Positive or negative edge clocking is available as well as advanced clocking features such as **complementary** and **biphase** clocking. Complementary clocking provides two clock lines exactly 180 degrees out of phase, and is useful in applications such as fast data paths. A biphase clock line clocks flip-flops on both the positive and negative edges of the clock. The configuration options for the four clock lines per PAL block are as follows:

Clock Line 0 Options

- ◆ Global clock (0, 1, 2, or 3) with positive or negative edge clock enable
- ◆ Product-term clock (A^*B^*C)
- ◆ Sum-term clock ($A+B+C$)

Clock Line 1 Options

- ◆ Global clock (0, 1, 2, or 3) with positive edge clock enable
- ◆ Global clock (0, 1, 2, or 3) with negative edge clock enable

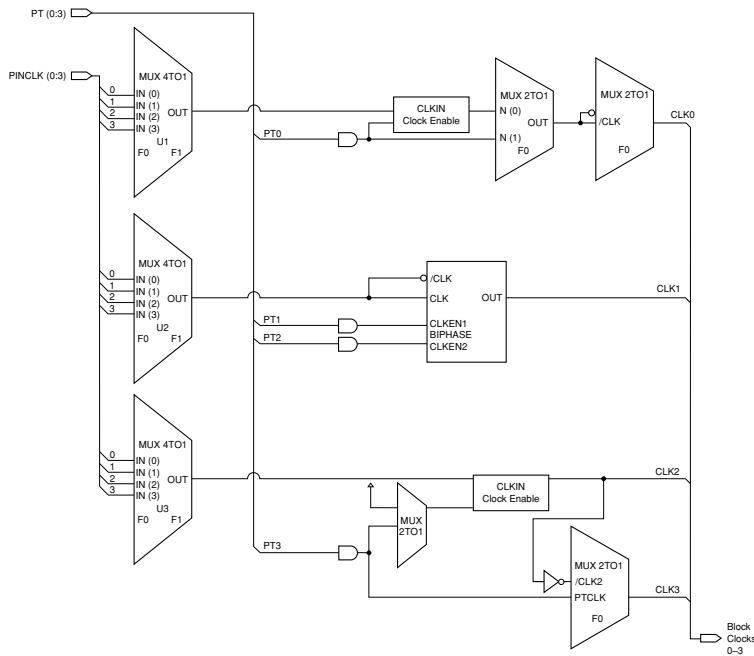
- ◆ Global clock (0, 1, 2, or 3) with positive and negative edge clock enable (biphase)

Clock Line 2 Options

- ◆ Global clock (0, 1, 2, or 3) with clock enable

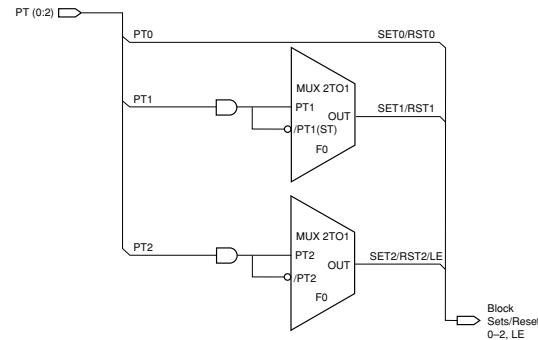
Clock Line 3 Options

- ◆ Complement of clock line 2 (same clock enable)
- ◆ Product-term clock (if clock line 2 does not use clock enable)



20446G-004

Figure 4. Clock Generator



20446G-005

Figure 5. Set/Reset Generator

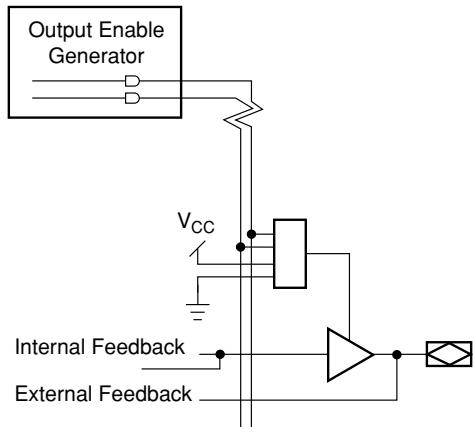
The set/reset generation portion of the control generator (Figure 5) creates three set/reset lines for the PAL block. Each macrocell can choose one of these three lines or choose no set/reset at all. All three lines can be configured for product term set/reset and two of the three lines can be configured as sum term set/reset and one of the lines can be configured as product-term or sum-term latch enable. While the set/reset signals are generated in the control generator, whether that signal sets or resets a flip-flop is determined within the individual macrocell. The same signal can set one flip-flop and reset another. PT2 or /PT2 can also be used as a latch enable for macrocells configured as latches.

Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
See Ordering Information section for product status.

OE Generator

There is one output enable (OE) generator per PAL block that generates two product-term driven output enables. Each I/O cell is simply an output buffer. Each I/O cell within the PAL block can choose to be permanently enabled, permanently disabled, or choose one of the two product term output enables per PAL block (Figure 6).



20446G-006

Figure 6. Output Enable Generator and I/O Cell

See Ordering Information section for product status.

Select devices have been discontinued.

MULTIPLE I/O AND DENSITY OPTIONS

The MACH 5 family offers six macrocell densities in a number of I/O options. This allows designers to choose a device close to their logic density and I/O requirements, thus minimizing costs. For the same package type, every density has the same pin-out. With proper design considerations, a design can be moved to a higher or lower density part as required.

IEEE 1149.1 - COMPLIANT BOUNDARY SCAN TESTABILITY

Most MACH 5 devices have boundary scan registers and are compliant to the IEEE 1149.1 standard. This allows functional testing of the circuit board on which the device is mounted through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test node data to be captured and shifted out for verification. In addition, these devices can be linked into a board-level serial scan path for more complete board-level testing.

IEEE 1149.1 - COMPLIANT IN-SYSTEM PROGRAMMING

Programming devices in-system provides a number of significant benefits including: rapid prototyping, lower inventory levels, higher quality, and the ability to make in-field modifications. All MACH 5 devices provide in-system programming (ISP) capability through their IEEE 1149.1-compliant Boundary Scan Test Access Port. By using the IEEE 1149.1-compliant Boundary Scan Test Access Port as the communication interface through which ISP is achieved, customers get the benefit of a standard, well-defined interface.

MACH 5 devices can be programmed across the commercial temperature and voltage range. The PC-based LatticePRO software facilitates in-system programming of MACH 5 devices. LatticePRO software takes the JEDEC file output produced by design implementation software, along with information about the Boundary Scan chain, and creates a set of vectors that are used to drive the Boundary Scan chain. LatticePRO software can use these vectors to drive a Boundary Scan chain via the parallel port of a PC. Alternatively, LatticePRO software can output files in formats understood by common automated test equipment. This equipment can then be used to program MACH 5 devices during the testing of a circuit board.

PCI COMPLIANT

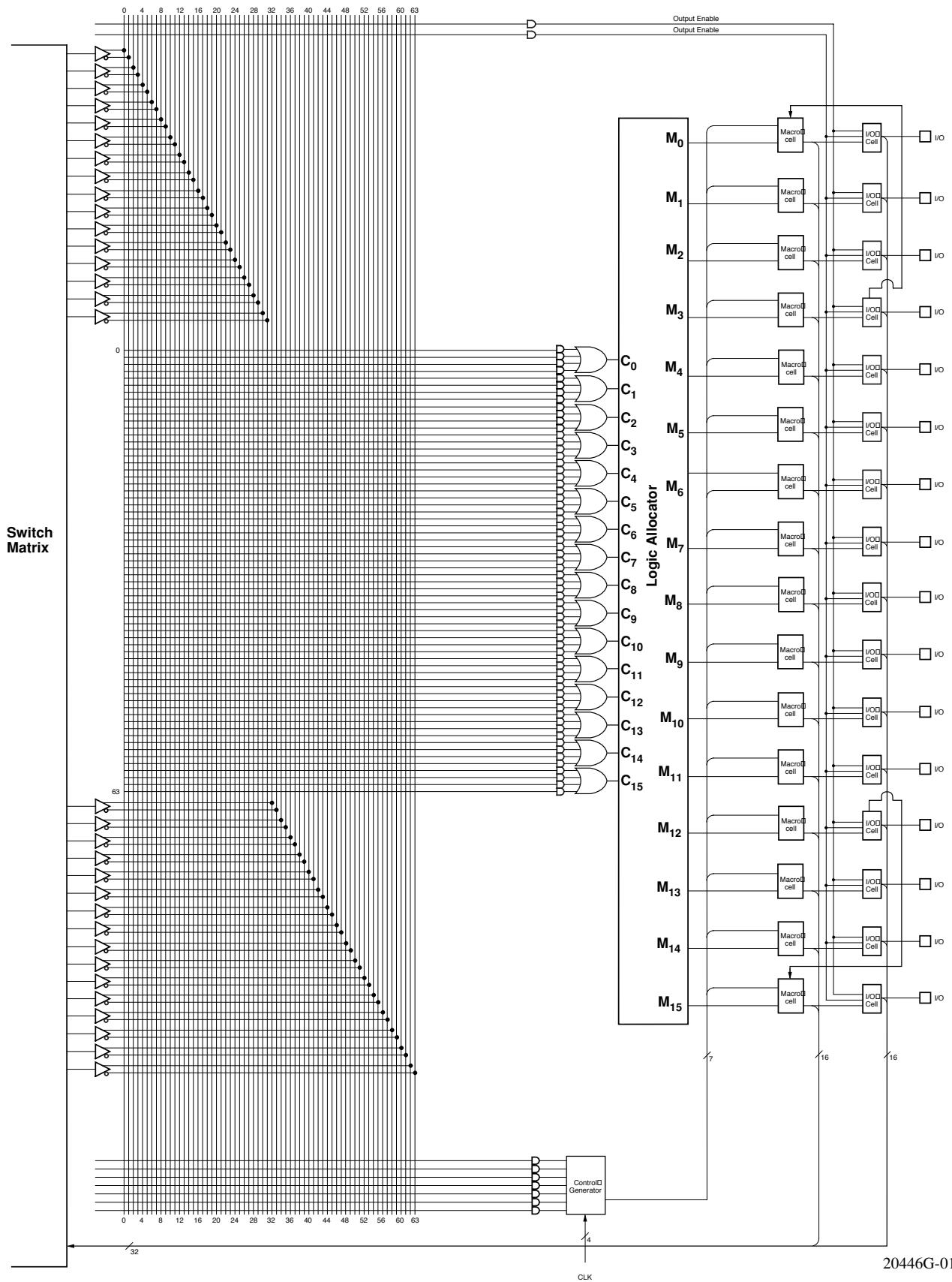
MACH 5 devices in the -5/-6/-7/-10/-12 speed grades are compliant with the *PCI Local Bus Specification* version 2.1, published by the PCI Special Interest Group (SIG). The 5-V devices are fully PCI-compliant. The 3.3-V devices are mostly compliant but do not meet the PCI condition to clamp the inputs as they rise above V_{CC} because of their 5-V input tolerant feature. MACH 5 devices provide the speed, drive, density, output enables and I/Os for the most complex PCI designs.

**Select devices have been discontinued.
See Ordering Information section for product status.**

SECURITY BIT

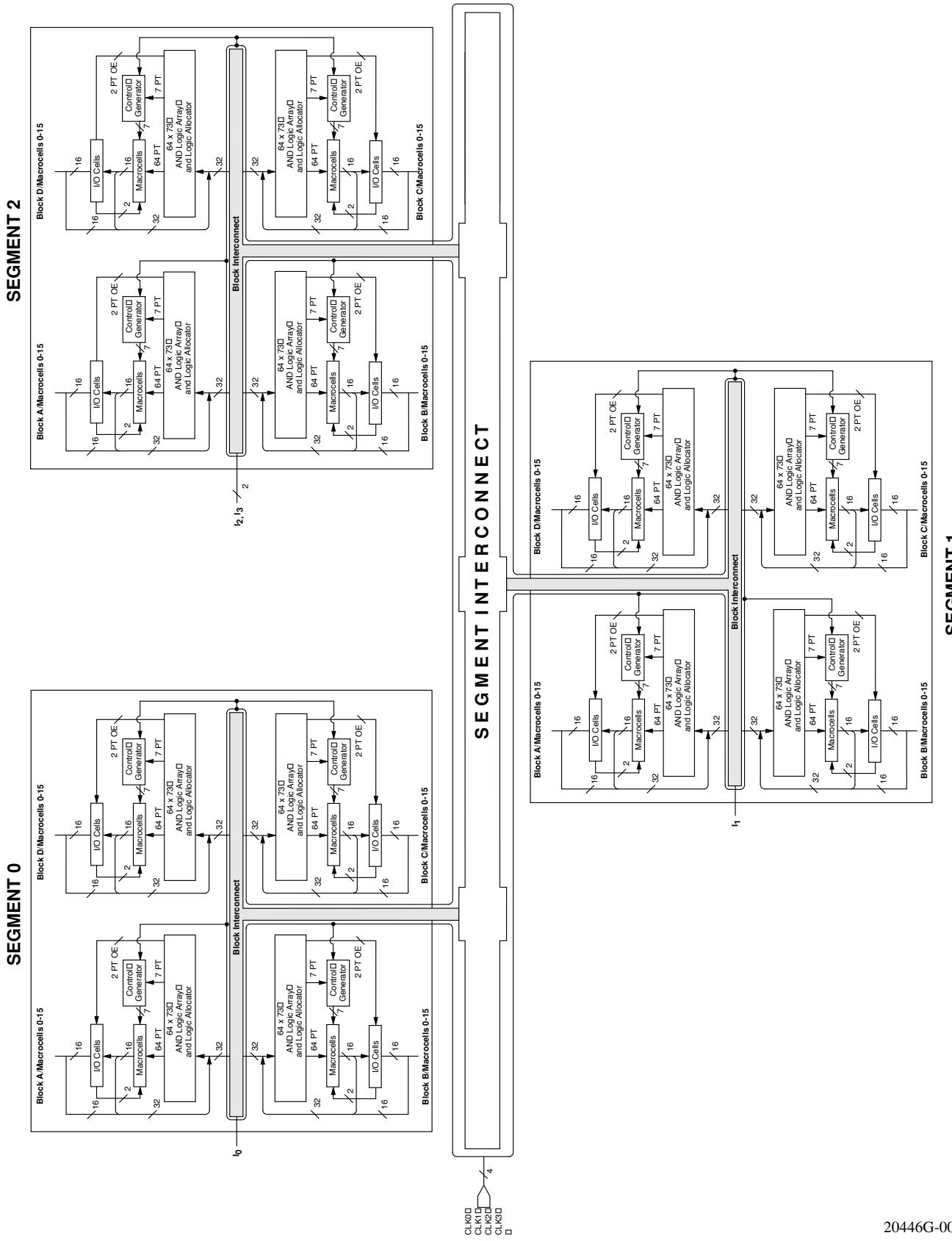
A programmable security bit is provided on the MACH 5 devices as a deterrent to unauthorized copying of the array configuration patterns. Once programmed, this bit defeats readback of the programmed pattern by a device programmer, securing proprietary designs from competitors. Programming and verification are also defeated by the security bit. The bit can only be reset by erasing the entire device.

MACH 5 PAL BLOCK



**Select devices have been discontinued.
See Ordering Information section for product status.**

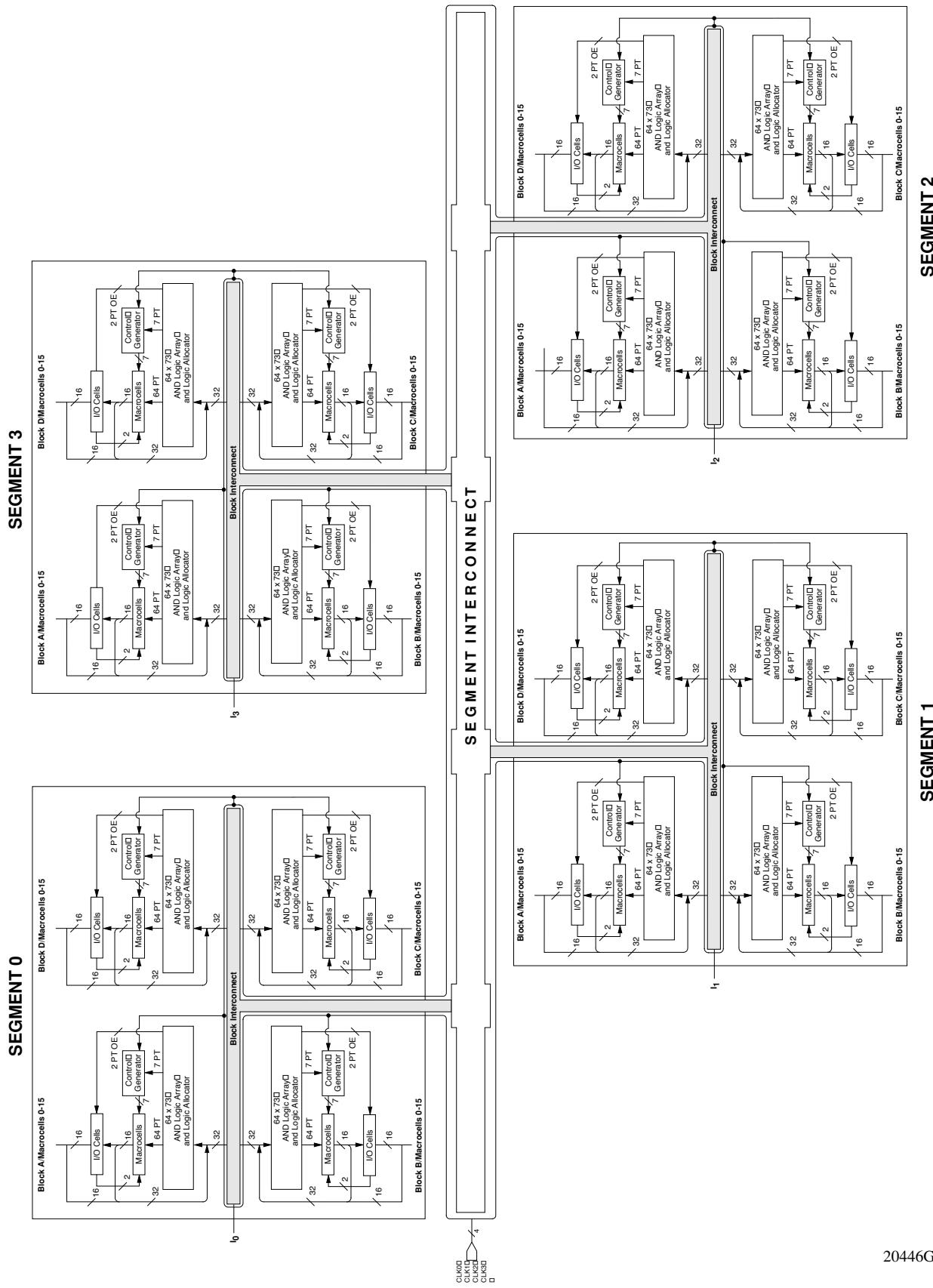
BLOCK DIAGRAM — M5-192/XXX



**Select devices have been discontinued.
See Ordering Information section for product status.**

Select devices have been discontinued.
See Ordering Information section for product status.

BLOCK DIAGRAM — M5(LV)-256/XXX

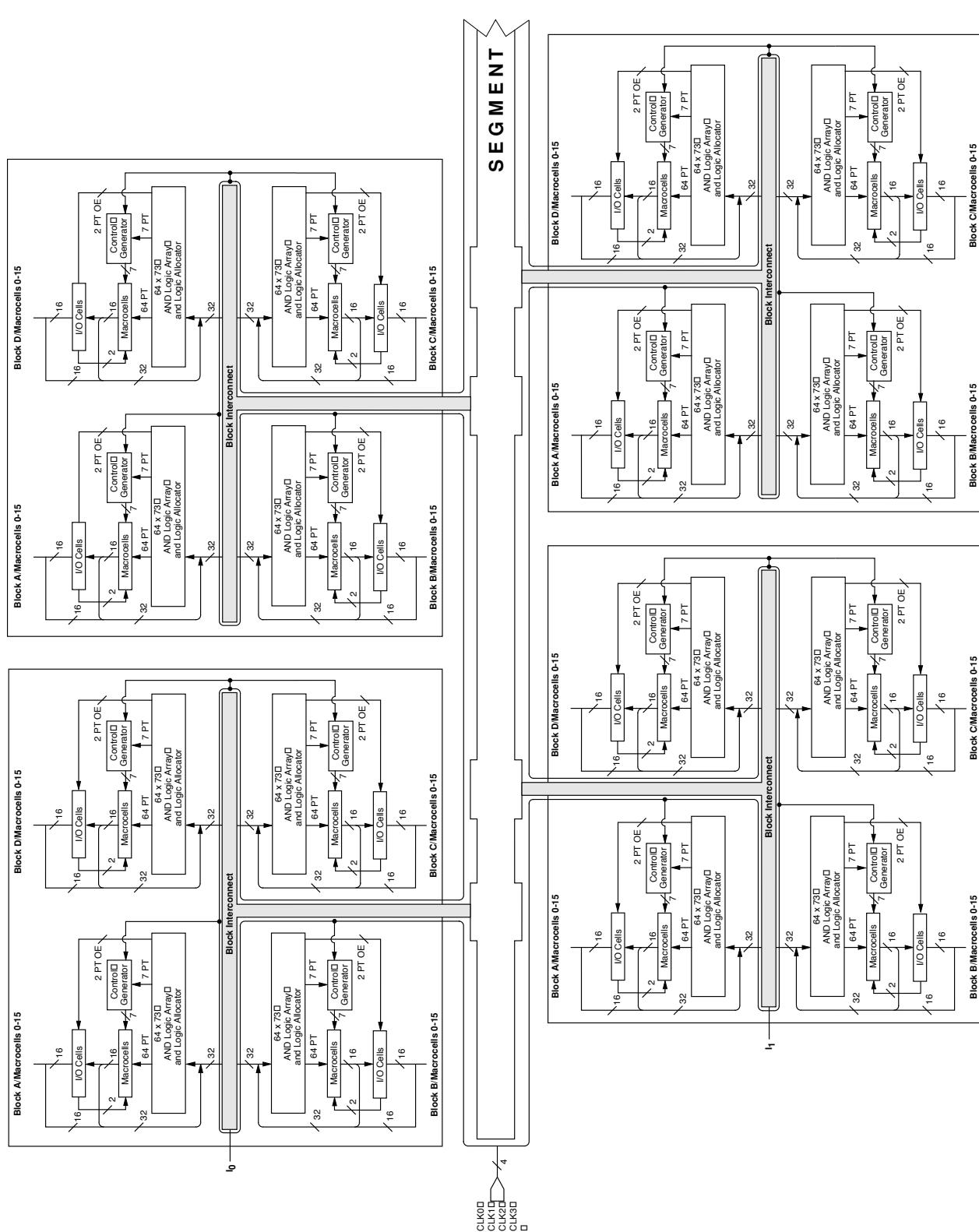


20446G-009

BLOCK DIAGRAM — M5(LV)-512/XXX

Continued

SEGMENT 0



SEGMENT 1

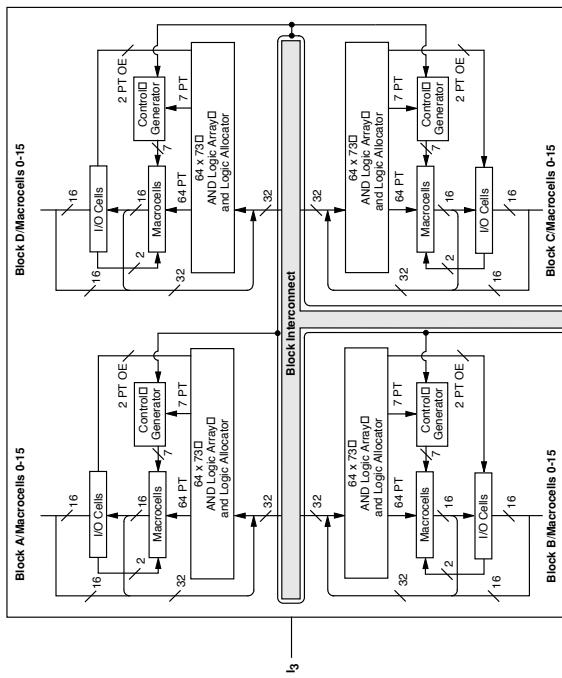
**Select devices have been discontinued.
See Ordering Information section for product status.**

SEGMENT 2

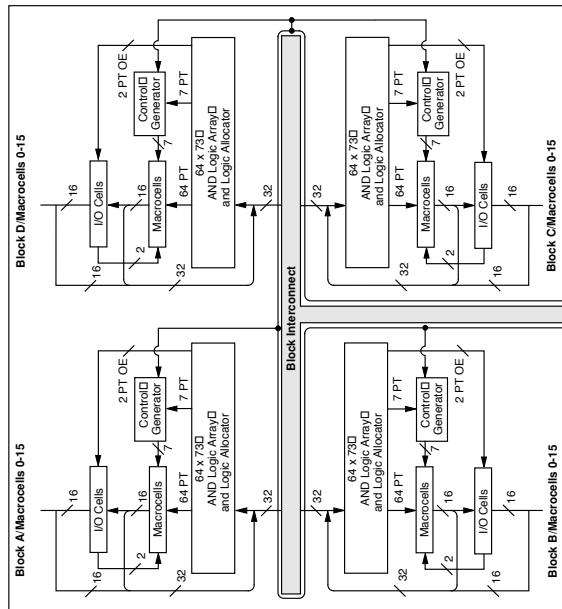
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See Ordering Information section for product status.**

BLOCK DIAGRAM — M5(LV)-512/XXX

SEGMENT 5



SEGMENT 6

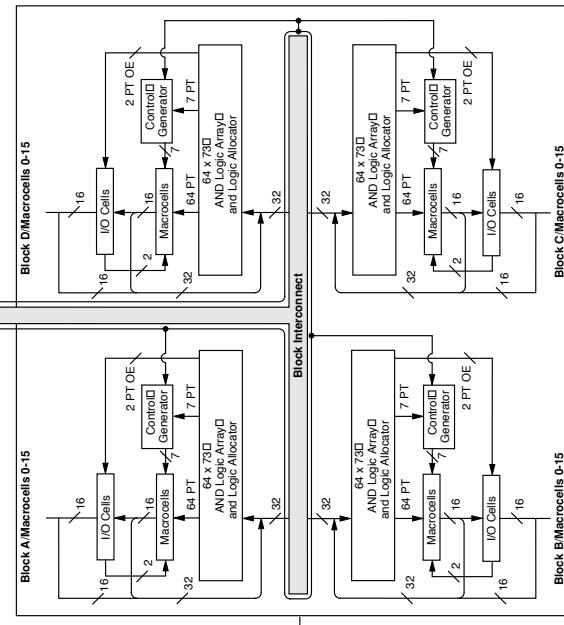


INTERCONNECT

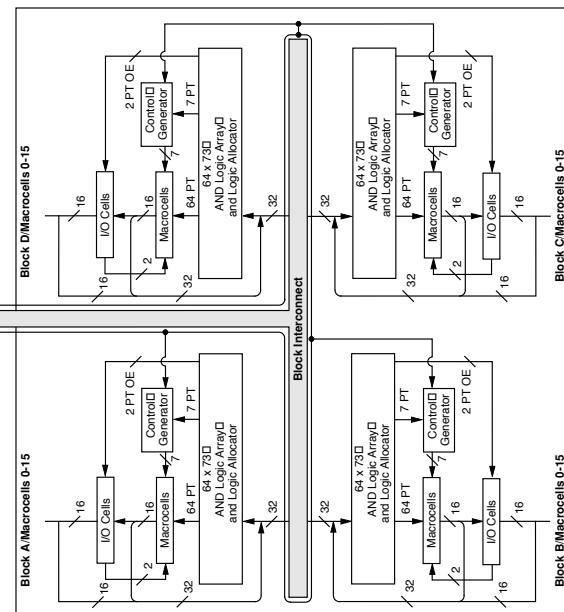
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**Select devices have been discontinued.
See Ordering Information section for product status.**

SEGMENT 4



SEGMENT 3



Select devices have been discontinued.
See Ordering Information section for product status.

ABSOLUTE MAXIMUM RATINGS

M5

Storage Temperature.....	-65°C to +150°C
Device Junction Temperature (Note 1).....	+130°C or +150°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to 5.5 V
Static Discharge Voltage.....	2000 V
Latchup Current (-40°C to +85°C)	200 mA
<i>Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability.</i>	

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (T_A)	
Operating in Free Air.....	0°C to +70°C
Supply Voltage (V_{CC}) with Respect to Ground.....	+4.75 V to +5.25 V

Industrial (I) Devices

Ambient Temperature (T_A)	
Operating in Free Air.....	-40°C to +85°C
Supply Voltage (V_{CC}) with Respect to Ground.....	+4.5 V to +5.5 V
<i>Operating ranges define those limits between which the functionality of the device is guaranteed.</i>	

5-V DC CHARACTERISTICS OVER OPERATING RANGES

Parameter Symbol	Parameter Description	Test Description	Min	Typ	Max	Unit
V_{OH}	Output HIGH Voltage (For M5-128/1, M5-192/1, M5-256/1, M5-320, M5-384, M5-512 Devices)	$I_{OH} = -3.2 \text{ mA}, V_{CC} = \text{Min}, V_{IN} = V_{IH} \text{ or } V_{IL}$	2.4			V
		$I_{OH} = -100 \mu\text{A}, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL}$		3.3	3.6	V
	Output HIGH Voltage (For M5-128, M5-192, M5-256 Devices)	$I_{OH} = -3.2 \text{ mA}, V_{CC} = \text{Min}, V_{IN} = V_{IH} \text{ or } V_{IL}$	2.4			V
		$I_{OH} = -2.5 \text{ mA}, V_{CC} = 5.25 \text{ V}, V_{IN} = V_{IH} \text{ or } V_{IL}$			3.6	V
V_{OL}	Output LOW Voltage (Note 2)	$I_{OL} = +16 \text{ mA}, V_{CC} = \text{Min}, V_{IN} = V_{IH} \text{ or } V_{IL}$			0.5	V
V_{IH}	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 3)	2.0			V
V_{IL}	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 3)			0.8	V
I_{IH}	Input HIGH Leakage Current	$V_{IN} = 5.25, V_{CC} = \text{Max}$ (Note 4)			10	μA
I_{IL}	Input LOW Leakage Current	$V_{IN} = 0, V_{CC} = \text{Max}$ (Note 4)			-10	μA
I_{OZH}	Off-State Output Leakage Current HIGH	$V_{OUT} = 5.25, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL}$ (Note 4)			10	μA
I_{OZL}	Off-State Output Leakage Current LOW	$V_{OUT} = 0, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL}$ (Note 4)			-10	μA
I_{SC}	Output Short-Circuit Current	$V_{OUT} = 0.5 \text{ V}, V_{CC} = \text{Max}, V_{IN} = V_{IH} \text{ or } V_{IL}$ (Note 5)	-30		-180	mA

Note:

- 150° for M5-128, M5-192 and M5-256 devices. 130° for M5-128/1, M5-192/1, M5-256/1, M5-320, M5-384 and M5-512 devices.
- Total I_{OL} between ground pins should not exceed 64 mA.
- These are absolute values with respect to device ground, and all overshoots due to system and/or tester noise are included.
- I/O pin leakage is the worst case of I_{IL} and I_{OZL} or I_{IH} and I_{OZH} .
- Not more than one output should be shorted at a time. Duration of the short-circuit should not exceed one second.

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES¹ (CONTINUED)

	-5		-6		-7		-10		-12		-15		-20		Unit	
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Frequency:																
f_{MAX}	External feedback, PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{COS})$	133		125		100		83.3		71.4		55.6		45.5		MHz
	Internal feedback, PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{COSi})$	182		167		125		100		83.3		62.5		50.0		MHz
	No feedback PAL block level. Min of $1/(t_{WLS} + t_{WHS})$ or $1/(t_{SS} + t_{HS})$	200		167		167		125		100		83.3		83.3		MHz
f_{MAXA}	External feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{COA})$	91		91		71.4		58.8		47.6		41.7		35.7		MHz
	Internal feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{COAi})$	111		111		83.3		66.7		52.6		45.5		38.5		MHz
	No feedback, PAL block level. Min of $1/(t_{WLA} + t_{WHA})$ or $1/(t_{SA} + t_{HA})$	167		125		125		100		83.3		71.4		62.5		MHz
f_{MAXI}	Maximum input register frequency $1/(t_{SIRS} + t_{HIRS})$ or $1/(2 \times t_{WICW})$	167		125		125		100		83.3		71.4		62.5		MHz

Notes:

1. See "MACH Switching Test Circuits" documentation on the Lattice Data Book CD-ROM or Lattice web site.
2. Numbers in parentheses are for M5-128, M5-192, M5-256.
3. If a signal is used as both a clock and a logic array input, then the maximum input frequency applies ($f_{MAX}/2$).

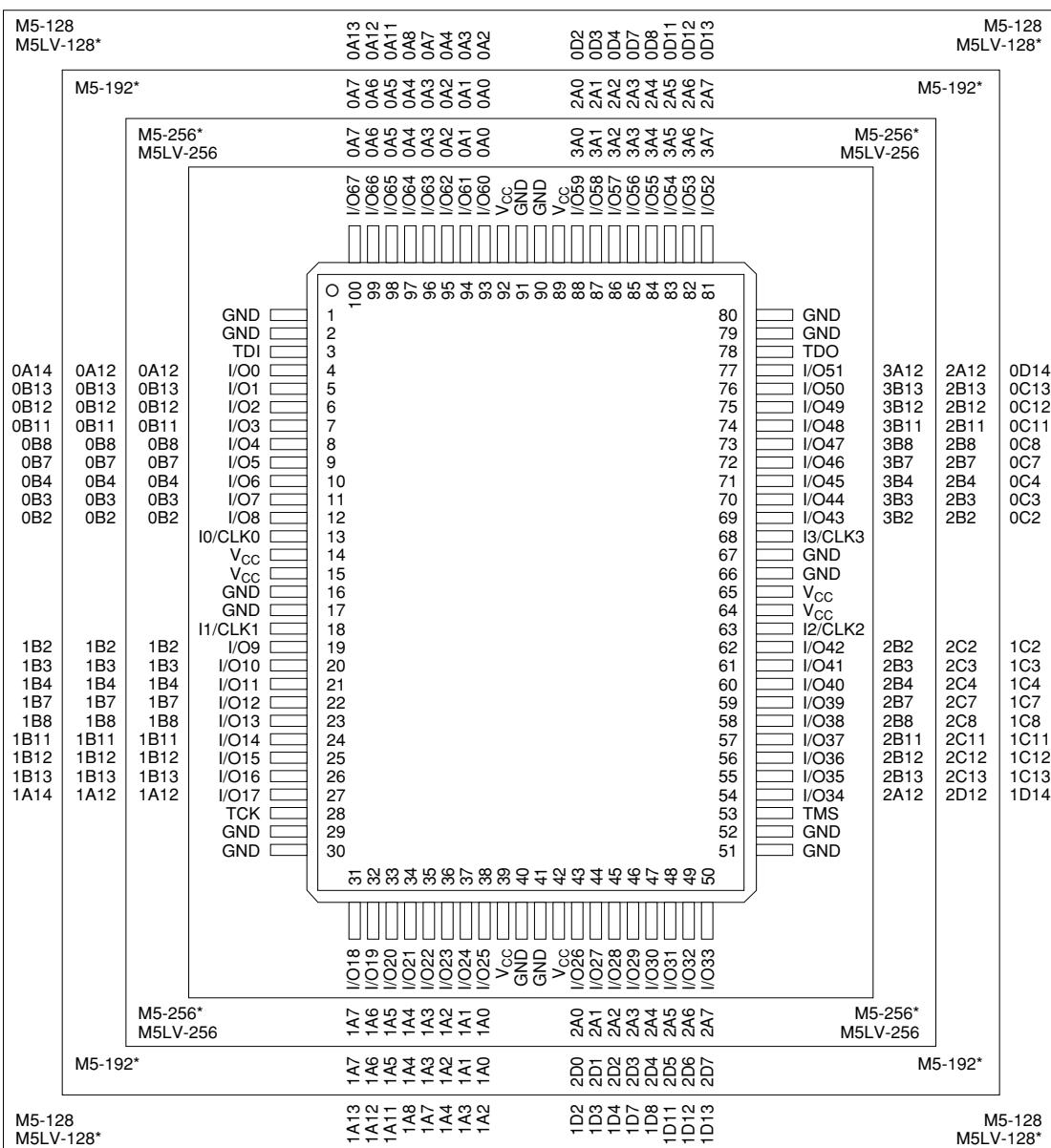
Select devices have been discontinued.
See Ordering Information section for product status.

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See Ordering Information section for product status.**

100-PIN PQFP CONNECTION DIAGRAM

Top View

100-Pin PQFP (68 I/O)

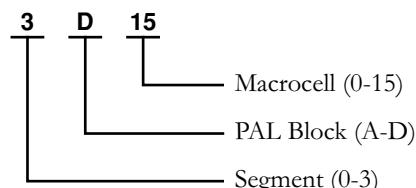


*Package obsolete, contact factory.

20446G-016

Pin Designations

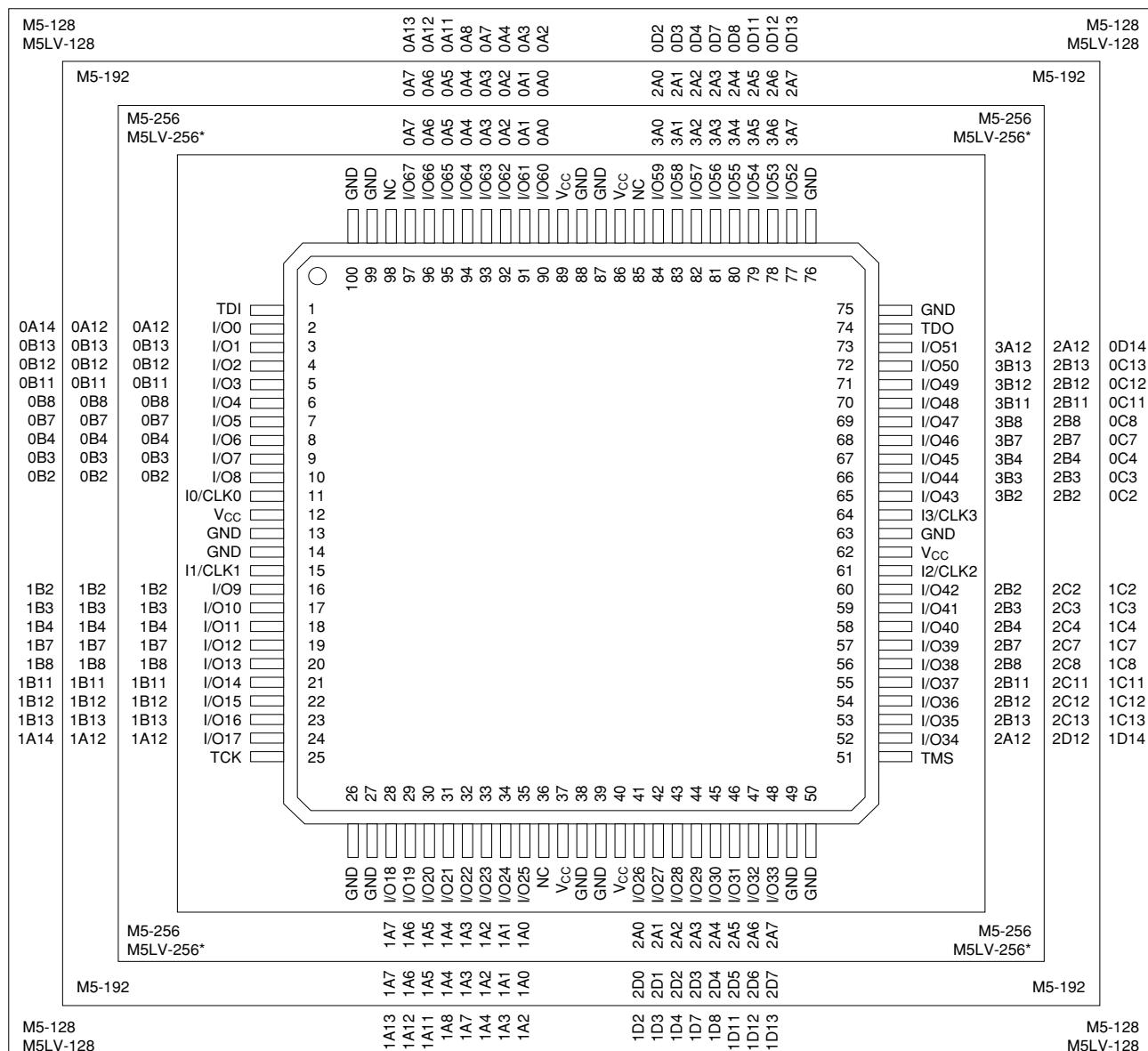
CLK	= Clock	V _{CC}	= Supply Voltage
GND	= Ground	TDI	= Test Data In
I	= Input	TCK	= Test Clock
I/O	= Input/Output	TMS	= Test Mode Select
NC	= No Connect	TDO	= Test Data Out



100-PIN TQFP CONNECTION DIAGRAM – 68 I/O

Top View

100-Pin TQFP (68 I/O)

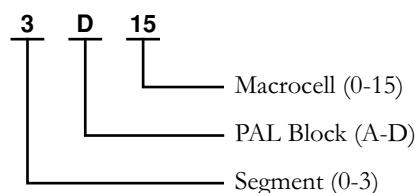


*Package obsolete, contact factory.

20446G-017

Pin Designations

CLK	= Clock	V _{CC}	= Supply Voltage
GND	= Ground	TDI	= Test Data In
I	= Input	TCK	= Test Clock
I/O	= Input/Output	TMS	= Test Mode Select
NC	= No Connect	TDO	= Test Data Out



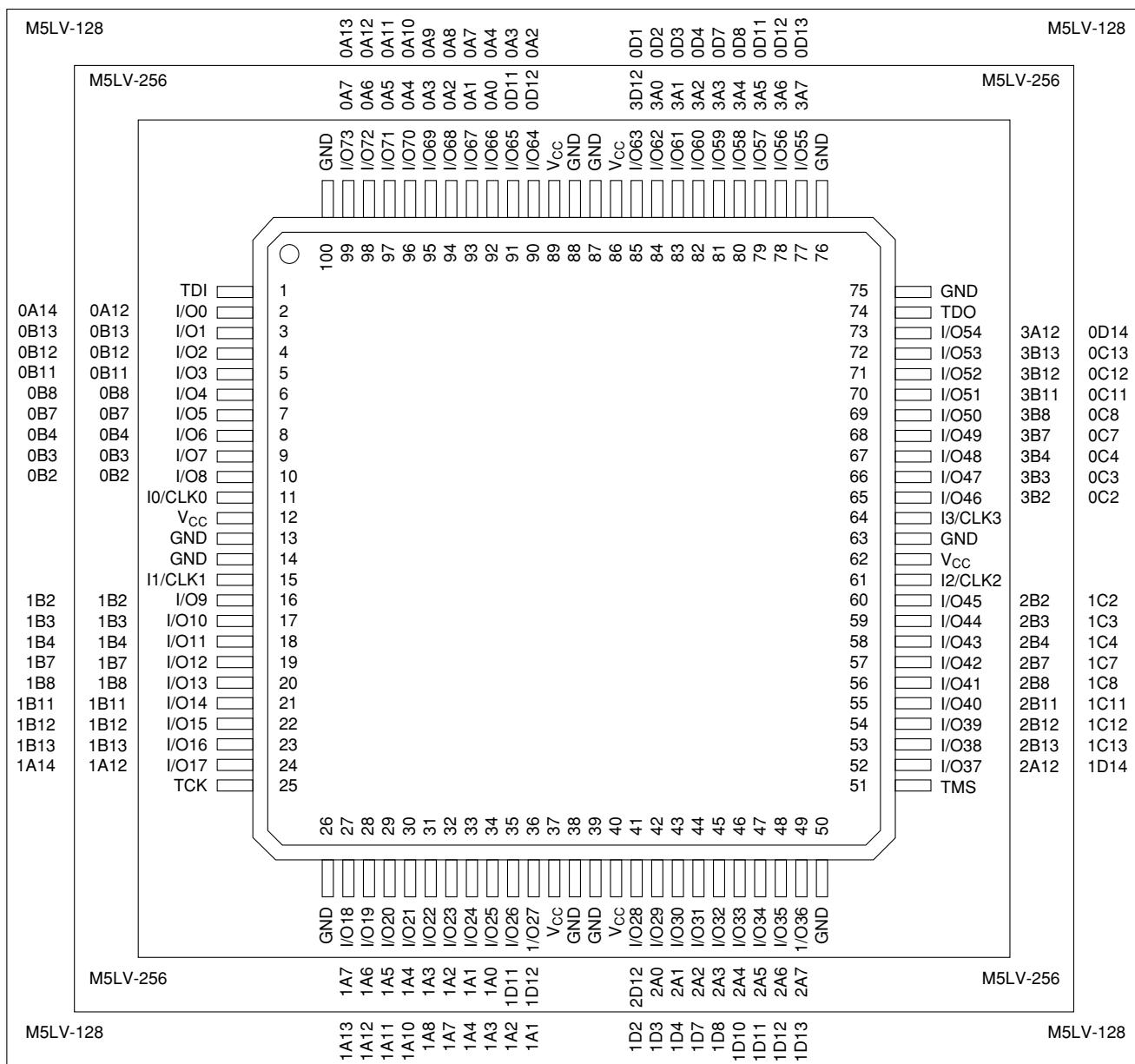
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See Ordering Information section for product status.

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See Ordering Information section for product status.

100-PIN TQFP CONNECTION DIAGRAM – 74 I/O

Top View

100-Pin TQFP (74 I/O)

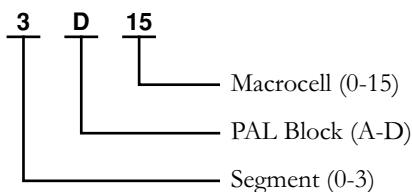


20446G-018

Pin Designations

CLK	= Clock
GND	= Ground
I	= Input
I/O	= Input/Output
NC	= No Connect

V _{CC}	= Supply Voltage
TDI	= Test Data In
TCK	= Test Clock
TMS	= Test Mode Select
TDO	= Test Data Out

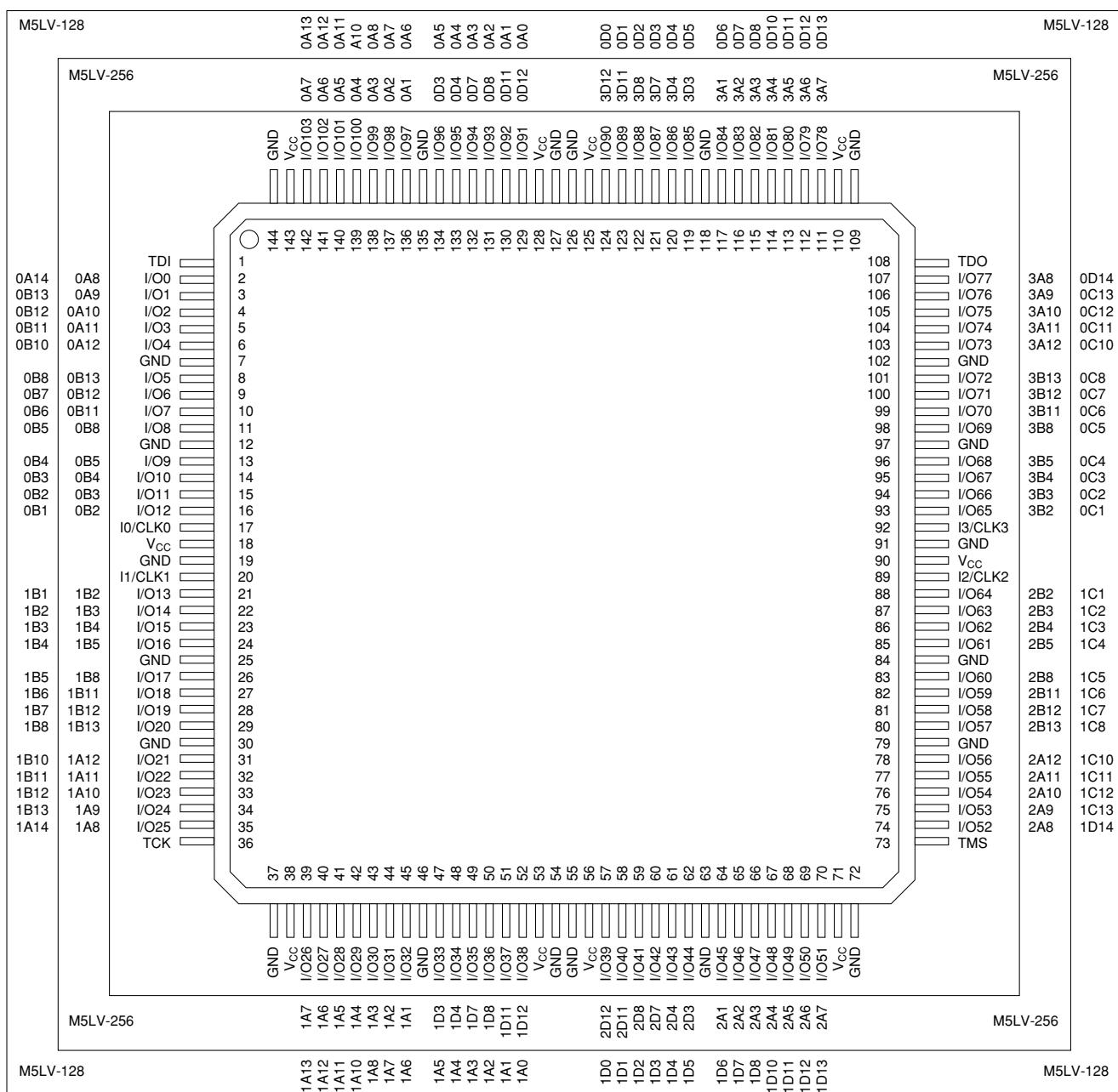


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See Ordering Information section for product status.

144-PIN TQFP CONNECTION DIAGRAM

Top View

144-Pin TQFP

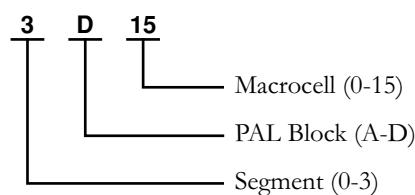


20446G-020

Pin Designations

CLK	= Clock
GND	= Ground
I	= Input
I/O	= Input/Output
NC	= No Connect

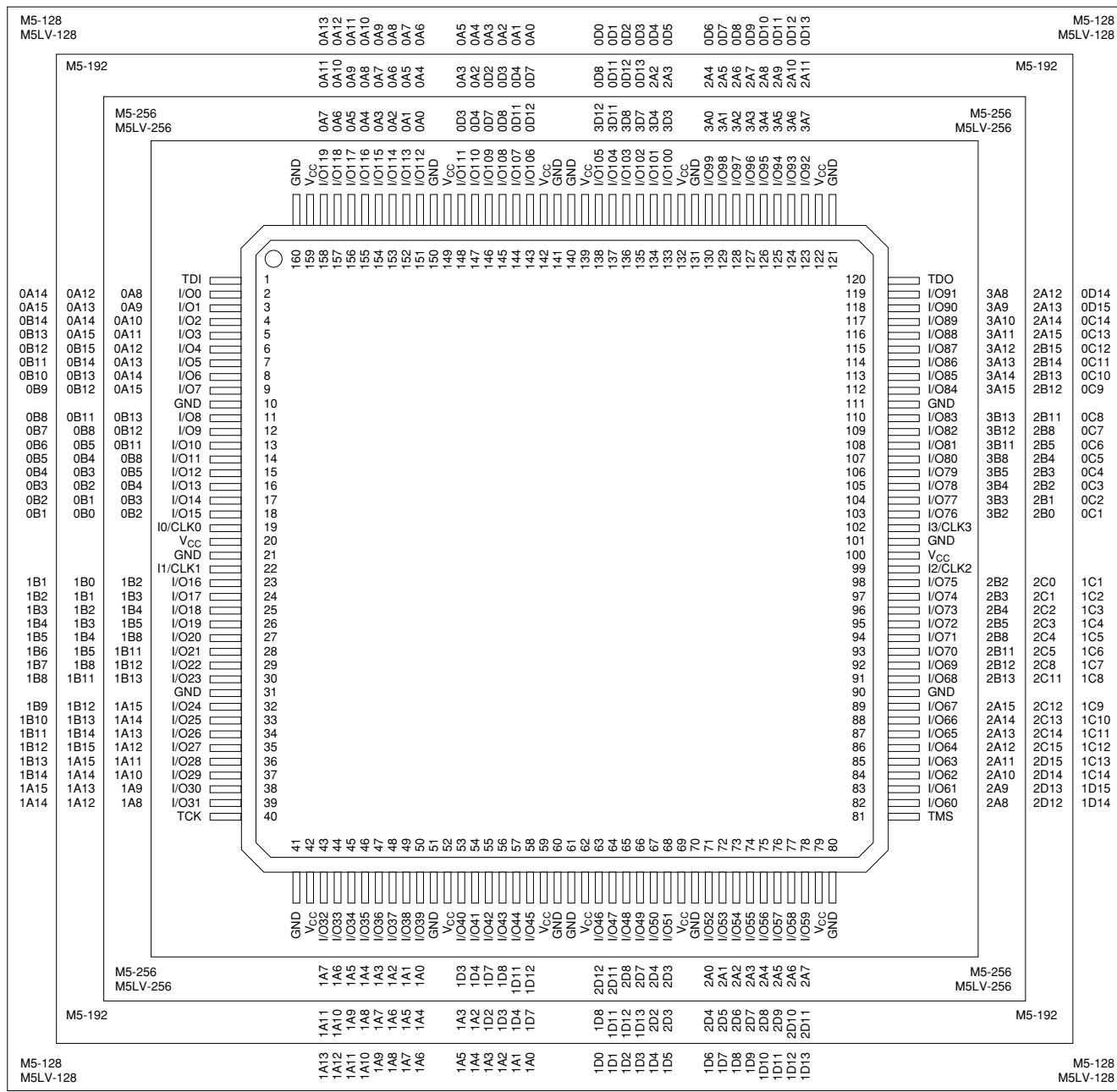
V _{CC}	= Supply Voltage
TDI	= Test Data In
TCK	= Test Clock
TMS	= Test Mode Select
TDO	= Test Data Out



160-PIN PQFP CONNECTION DIAGRAM

Top View

160-Pin PQFP (128, 192, 256 Macrocells)



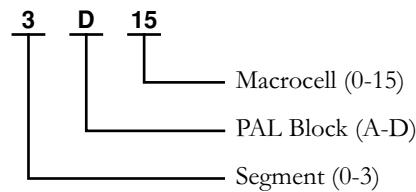
20446G-021

Select devices have been discontinued.
See Ordering Information section for product status.

Pin Designations

CLK	= Clock
GND	= Ground
I	= Input
I/O	= Input/Output
NC	= No Connect

V _{CC}	= Supply Voltage
TDI	= Test Data In
TCK	= Test Clock
TMS	= Test Mode Select
TDO	= Test Data Out



256-BALL BGA CONNECTION DIAGRAM — M5-320

Bottom View (I/O Pin-outs)

256-Ball BGA

	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	GND	I/O11	GND	I/O44	I/O58	GND	I/O70	I/O76	GND	GND	I/O108	I/O116	GND	I/O128	I/O134	GND	GND	GND	A		
B	GND	I/O12	I/O28	I/O45	I/O59	I/O64	I/O71	I/O77	I/O84	I/O90	I/O96	I/O102	I/O117	I/O122	I/O129	I/O135	I/O148	I/O164	GND	B	
C	I/O0	I/O13	V _{CC}	I/O46	I/O60	I/O65	I/O72	I/O78	I/O85	I/O91	I/O97	I/O103	I/O110	I/O118	I/O123	I/O130	I/O136	V _{CC}	I/O165	I/O181	C
D	I/O1	I/O14	I/O29	V _{CC}	V _{CC}	I/O66	V _{CC}	I/O79	I/O86	I/O92	I/O98	I/O104	I/O111	V _{CC}	I/O124	V _{CC}	V _{CC}	I/O149	I/O166	I/O182	D
E	I/O2	I/O15	I/O30	TDI										TDO	I/O150	I/O167	I/O183	E			
F	GND	I/O16	I/O31	I/O47										I/O137	I/O151	I/O168	GND	F			
G	I/O3	I/O17	I/O32	V _{CC}										V _{CC}	I/O152	I/O169	I/O184	G			
H	GND	I/O18	I/O33	I/O48										I/O138	I/O153	I/O170	GND	H			
J	I/O4	I/O19	I/O34	I/O49										I/O139	I/O154	I/O171	I/O185	J			
K	GND	I/O1CK0	I/O35	I/O50										I/O140	I/O155	I ₃ /CLK3	I/O186	K			
L	I/O5	I ₁ /CLK1	I/O36	I/O51										I/O141	I/O156	I ₂ /CLK2	GND	L			
M	I/O6	I/O20	I/O37	I/O52										I/O142	I/O157	I/O172	I/O187	M			
N	GND	I/O21	I/O38	I/O53										I/O143	I/O158	I/O173	GND	N			
P	I/O7	I/O22	I/O39	V _{CC}										V _{CC}	I/O159	I/O174	I/O188	P			
R	GND	I/O23	I/O40	I/O54											I/O144	I/O160	I/O175	GND	R		
T	I/O8	I/O24	I/O41	TCK										TMS	I/O161	I/O176	I/O189	T			
U	I/O9	I/O25	I/O42	V _{CC}	V _{CC}	I/O67	V _{CC}	I/O80	I/O87	I/O93	I/O99	I/O105	I/O112	V _{CC}	I/O125	V _{CC}	V _{CC}	I/O162	I/O177	I/O190	U
V	I/O10	I/O26	V _{CC}	I/O55	I/O61	I/O68	I/O73	I/O81	I/O88	I/O94	I/O100	I/O106	I/O113	I/O119	I/O126	I/O131	I/O145	V _{CC}	I/O178	I/O191	V
W	GND	I/O27	I/O43	I/O56	I/O62	I/O69	I/O74	I/O82	I/O89	I/O95	I/O101	I/O107	I/O114	I/O120	I/O127	I/O132	I/O146	I/O163	I/O179	GND	W
Y	GND	GND	GND	I/O57	I/O63	GND	I/O75	I/O83	GND	GND	GND	GND	I/O115	I/O121	GND	I/O133	I/O147	GND	I/O180	GND	Y

Pin Designations

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- V_{CC} = Supply Voltage
- TDI = Test Data In
- TCK = Test Clock
- TMS = Test Mode Select
- TDO = Test Data Out

Select devices have been discontinued.
See Ordering Information section for product status.

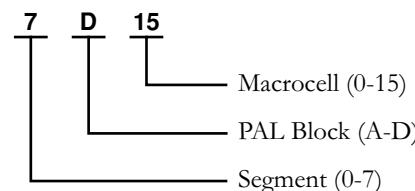
352-BALL BGA CONNECTION DIAGRAM — M5-512, M5LV-512

Bottom View (Macrocell Association)

	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	NC	GND	NC	7A10	GND	7A5	7A0	7B1	GND	7B7	NC	7B14	GND	6B14	6B10	6B6	GND	6B1	6A1	GND	NC	GND	NC	NC	NC	NC	A
B	NC	GND	NC	7A13	7A9	7A6	7A2	7B0	7B3	7B6	7B10	7B13	7B15	6B13	6B9	6B5	6B2	6A0	6A4	6A6	6A9	6A12	6A14	GND	NC	NC	B
C	GND	0A1	TDI	7A14	7A11	7A7	7A3	7A1	7B2	7B5	7B9	7B12	6B15	6B12	6B8	6B4	6B0	6A2	6A5	6A8	6A10	6A13	NC	NC	NC	NC	C
D	0A6	0A3	0A2	V _{CC}	7A15	7A12	7A8	7A4	V _{CC}	7B4	7B8	7B11	V _{CC}	6B11	6B7	6B3	V _{CC}	6A3	6A7	6A11	6A15	V _{CC}	TDO	5A1	5A2	GND	D
E	NC	0A8	0A5	0A0																			5A0	5A4	5A5	NC	E
F	GND	0A9	0A7	0A4																			5A3	5A7	5A9	5A12	F
G	0A13	0A12	0A10	V _{CC}																			5A6	5A8	5A14	GND	G
H	0D15	0A15	0A14	0A11																			V _{CC}	5A10	5A15	5D15	H
J	GND	0D13	0D14	V _{CC}																			5A11	5A13	5D13	5D11	J
K	0D9	0D10	0D11	0D12																			V _{CC}	5D14	5D10	GND	K
L	0D5	0D6	0D7	0D8																			5D12	5D9	5D8	5D6	L
M	0D1	0D2	0D4	0D3																			5D7	5D5	5D4	5D3	M
N	GND	0D0	I _O CLK0	V _{CC}																			5D2	5D1	5D0	I ₃ CLK3	N
P	I ₁ CLK1	1D0	1D1	1D2																			V _{CC}	I ₂ CLK2	4D0	GND	P
R	1D3	1D4	1D5	1D7																			4D3	4D4	4D2	4D1	R
T	1D6	1D8	1D9	1D12																			4D8	4D7	4D6	4D5	T
U	GND	1D10	1D14	V _{CC}																			4D12	4D11	4D10	4D9	U
V	1D11	1D13	1A13	1A11																			V _{CC}	4D14	4D13	GND	V
W	1D15	1A15	1A10	V _{CC}																			4A11	4A14	4A15	4D15	W
Y	GND	1A14	1A8	1A6																			V _{CC}	4A10	4A12	4A13	Y
AA	1A12	1A9	1A7	1A3																			4A4	4A7	4A9	GND	AA
AB	NC	1A5	1A4	1A0																			4A0	4A5	4A8	NC	AB
AC	GND	1A2	1A1	TCK	V _{CC}	2A15	2A11	2A7	2A3	V _{CC}	2B3	2B7	2B11	V _{CC}	3B3	3B7	3B3	V _{CC}	3A2	3A6	3A10	3A14	V _{CC}	4A2	4A3	4A6	AC
AD	NC	NC	NC	2A13	2A10	2A8	2A5	2A2	2B0	2B4	2B8	2B12	2B15	3B12	3B8	3B4	3B1	3A1	3A4	3A8	3A11	3A15	TMS	4A1	GND	AD	
AE	NC	NC	GND	2A14	2A12	2A9	2A6	2A4	2A0	2B2	2B5	2B9	2B13	3B15	3B9	3B5	3B2	3B0	3A3	3A7	3A9	3A13	NC	GND	NC	AE	
AF	NC	NC	GND	NC	GND	NC	GND	2A1	2B1	GND	2B6	2B10	2B14	GND	3B14	3B10	3B6	GND	NC	3A0	3A5	GND	3A12	NC	GND	NC	AF
	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	

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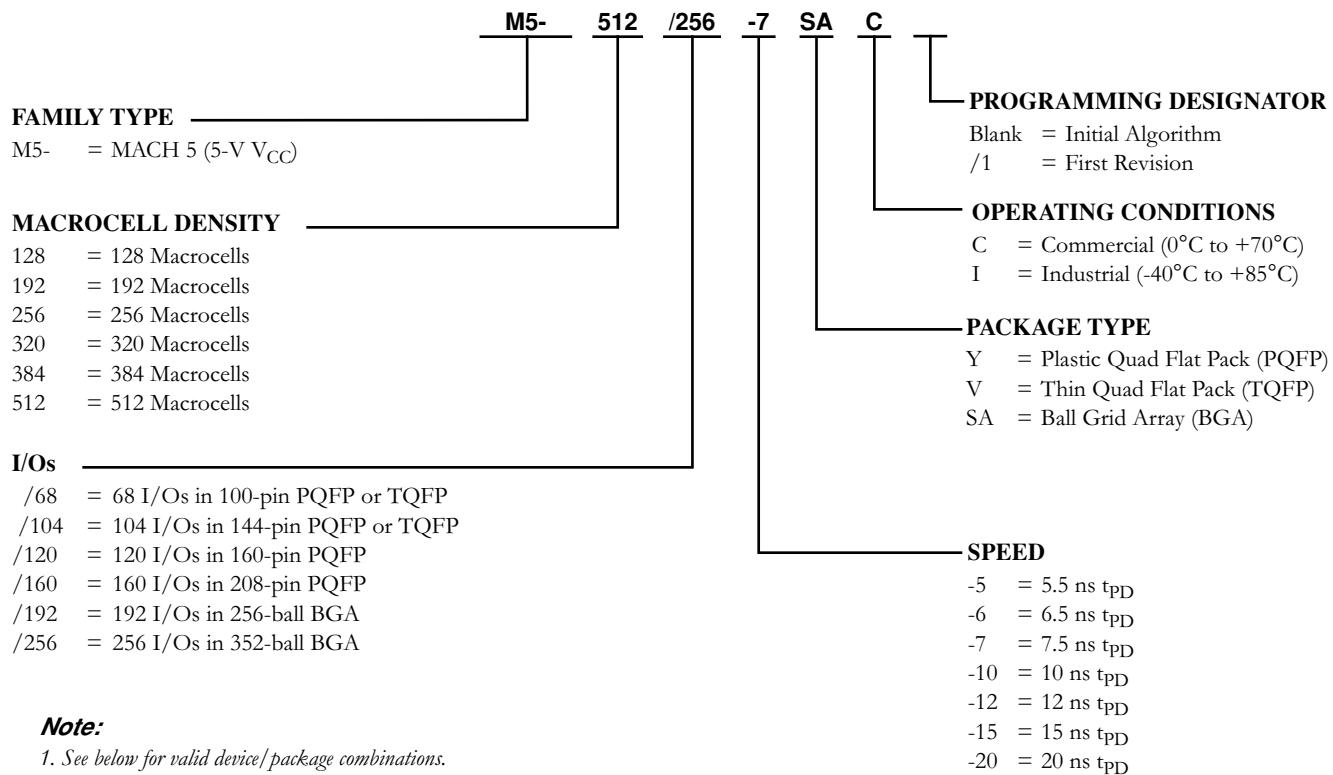
20446G-031

Select devices have been discontinued.
See Ordering Information section for product status.

Select devices have been discontinued.
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5V M5 ORDERING INFORMATION^{1,2}

Lattice standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.



Note:

1. See below for valid device/package combinations.
2. M5-128/1, M5-192/1 and M5-256/1 recommended for new designs.

Valid Combinations		
M5-128/68		YC, VC, YI, VI
M5-128/104		YC ¹ , YI ¹
M5-128/120	Commercial:	YC, YI
M5-192/68	-5, -7, -10, -12, -15	VC, VI
M5-192/120	Industrial:	YC, YI
M5-256/68	-7, -10, -12, -15, -20	VC, VI
M5-256/120		YC, YI
M5-256/160		YC, YI

Device Marking

Actual device marking differs from the ordering part number (OPN). All MACH devices are dual-marked with both Commercial and Industrial grades. The Industrial grade is slower, i.e., M5-512/256-7AC-10AI.

1. M5-128/104-xxYC/1 and M5-128/104-xxYI/1 have been discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

Valid Combinations		
M5-320/160	Commercial:	YC, YI
M5-320/192		SAC, SAI
M5-384/160	-6, -7, -10, -12, -15	YC, YI
M5-512/160	Industrial:	YC, YI
M5-512/256	-7, -10, -12, -15, -20	SAC, SAI

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local Lattice sales office to confirm availability of specific valid combinations and to check on newly released combinations.